November 2008

FAIRCHILD

SEMICONDUCTOR®

FGA70N33BTD **330V, 70A PDP IGBT**

Features

- High current capability
- ٠ Low saturation voltage: V_{CE(sat)} =1.7V @ I_C = 70A
- High input impedance
- Fast switching •
- RoHS Compliant •

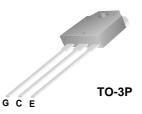
Applications

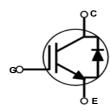
PDP System



General Description

Using Novel Trench IGBT Technology, Fairchild's new series of trench IGBTs offer the optimum performance for PDP applications where low conduction and switching losses are essential.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description		Ratings	Units
V _{CES}	Collector to Emitter Voltage		330	V
V _{GES}	Gate to Emitter Voltage		± 30	V
I _{Cpulse(1)} *	Pulsed Collector Current @	T _C = 25°C	160	А
I _{C pulse(2)} *	Pulsed Collector Current @	T _C = 25°C	220	А
P _D	Maximum Power Dissipation @	T _C = 25 ^o C	149	W
• D	Maximum Power Dissipation @	$T_{\rm C} = 100^{\rm o}{\rm C}$	60	W
V _{RRM}	Peak Repetitive Reverse Voltage of Diode		330	V
I _{F(AV)}	Average Rectified Forward Current of diode @ $T_C = 100^{\circ}C$		10	А
I _{FSM}	Non-repetitive Peak Surge Current of diode 60Hz Single Half-Sine wave		100	A
T _J , T _{stg}	Operating Junction Temperature and Storage Temperrature		-55 to +150	°C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units	
$R_{\theta JC}$ (IGBT)	Thermal Resistance, Junction to Case		0.84	°C/W	
$R_{\theta JC}$ (Diode)	Thermal Resistance, Junction to Case		1.57	°C/W	
R_{\thetaJA}	Thermal Resistance, Junction to Ambient		40	°C/W	

Notes:

1: Repetitive test , Pulse width=100usec , Duty=0.1 2: Half Sine Wave, D< 0.01, pluse width < 5usec

*I_C_pulse limited by max Tj

>	(Qty	
•	Box	
	Units	
	V	
	V/ºC	
	μA	
	nA	
	V	
	V	

Device N	larking	Device	Pa	Packaging ackage Type		Qty pe	er Tube		c Qty Box
		TO-3P Tube		30ea					
=lectric Symbol	al Char	Parameter		-	5°C unless otherwise noted	Min.	Тур.	Max.	Units
.,							71	-	
Off Charac	teristics								
BV _{CES}	Collector	to Emitter Breakdown Vo	ltage	$V_{GE} = 0V, I_C$	= 250μA	330			V
ΔB _{VCES} / ΔT _J	Temperate Voltage	ure Coefficient of Breakd	lown	$V_{GE} = 0V, I_C$	= 250uA		0.3		V/ºC
I _{CES}	Collector	Cut-Off Current		$V_{CE} = V_{CES}$	$V_{GE} = 0V$			250	μA
I _{GES}	G-E Leak	age Current		$V_{GE} = V_{GES}, V_{CE} = 0V$				±400	nA
On Charac	aristics								
V _{GE(th)}		shold Voltage		$I_C = 250 \mu A, V_{CE} = V_{GE}$		2.3	3.3	4.3	V
V _{CE(sat)}	Collector to Emitter Saturation Voltage		I _C = 20A, V _{GE} = 15V			1.1		V	
			I _C = 40A, V _G			1.4		V	
			I _C = 70A, V _G	_E = 15V, T _C = 25 ^o C		1.7		V	
			I _C = 70A, V _{GE} = 15V, T _C = 125°C			1.8		V	
				C					
Dynamic C				[1000		-
C _{ies}	Input Cap			V _{CE} = 30V, V _{GE} = 0V,			1380		pF
C _{oes}	Output Capacitance			f = 1MHz			140		pF
C _{res}		Fransfer Capacitance					60		pF
Switching (12		
t _{d(on)} t	Rise Time	Delay Time		V _{CC} = 200V,	I _C = 20A,		13 26		ns ns
t _r		, Delay Time		$R_G = 5\Omega, V_G$	_{GE} = 15V,		46		ns
u _{d(off)} t _f	Fall Time			Resistive Load, $T_C = 25^{\circ}C$			198		ns
t _{d(on)}		Delay Time					130		ns
	Rise Time	•		$V_{CC} = 200V,$			28		ns
t _{d(off)}		Delay Time		$R_G = 5\Omega$, $V_{GE} = 15V$, Resistive Load, $T_C = 125^{\circ}C$			48		ns
t _f	Fall Time				aa, 16 - 120 0		268		ns
Q _g	Total Gate	e Charge					49		nC
Q _{ge}		mitter Charge		$V_{CE} = 200V,$	I _C = 20A,		6.8		nC
Q _{gc}	Coto to C	ollector Charge		V _{GE} = 15V			17.5		nC

Symbol	Parameter	Test Conditio	Min.	Тур.	Max	Units	
V _{FM}	Diode Forward Voltage	I _F = 10A	$T_C = 25^{\circ}C$		1.1	1.5	V
FM Diodo Formard Voltago	.F .07.	T _C = 125°C		0.95] `	
t _{rr} Diode Reverse Recovery Time		$T_{\rm C} = 25^{\rm o}{\rm C}$		23		ns	
		I _F =10A, dI/dt = 200A/μs	T _C = 125 ^o C		36		
	Diode Peak Reverse Recovery		$T_{C} = 25^{\circ}C$		2.8		А
'rr	Current		$T_{C} = 125^{\circ}C$		5.1] ``
Q _{rr}	Diode Reverse Recovery Charge		$T_{\rm C} = 25^{\rm o}{\rm C}$		32		nC
∽II.			$T_{\rm C} = 125^{\rm o}{\rm C}$		91		

Typical Performance Characteristics



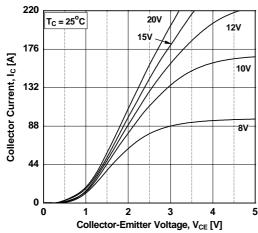


Figure 3. Typical Saturation Voltage Characteristics

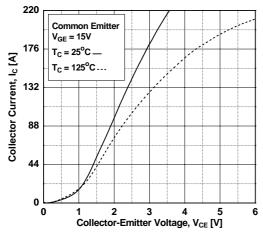


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

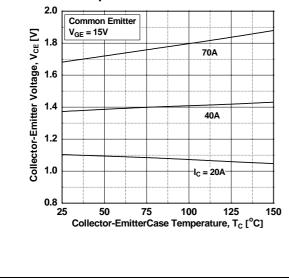


Figure 2. Typical Output Characteristics

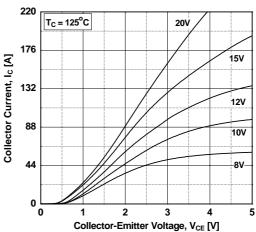


Figure 4. Transfer Characteristics

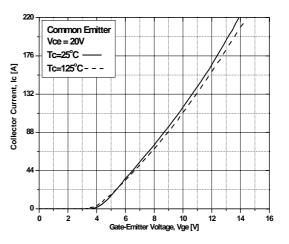
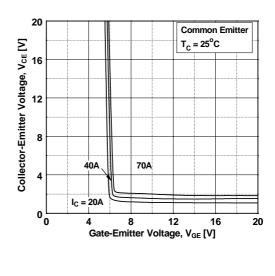
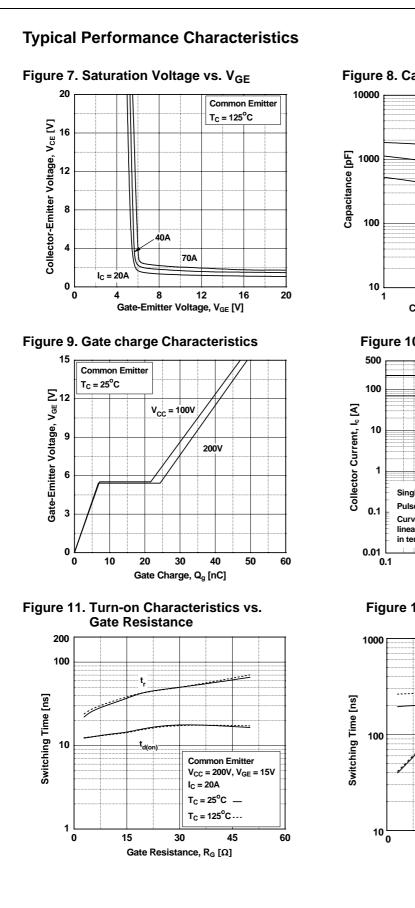
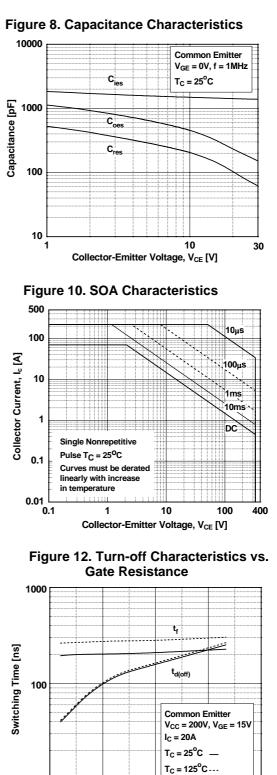


Figure 6. Saturation Voltage vs. V_{GE}







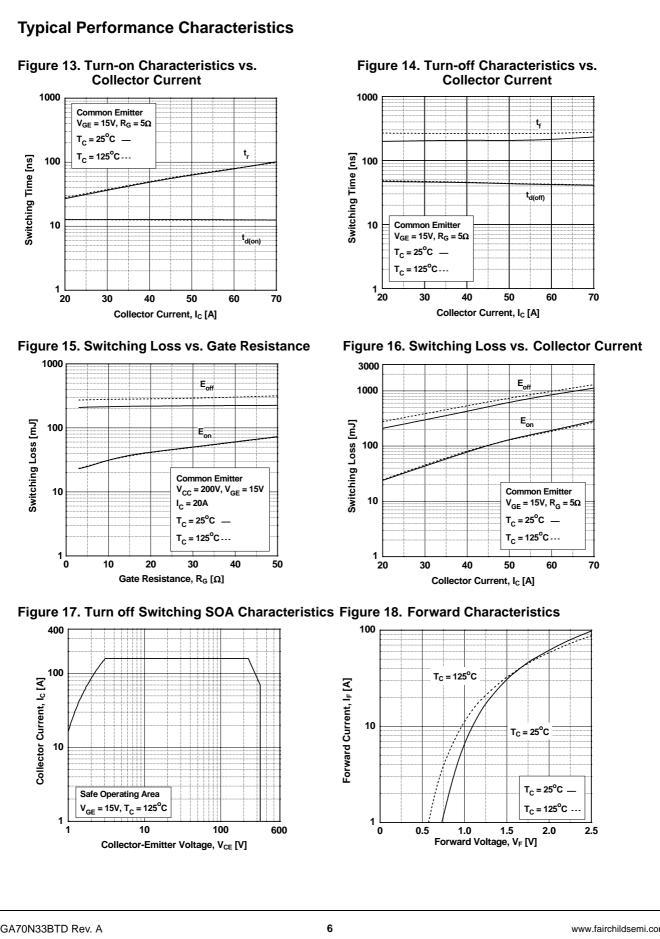
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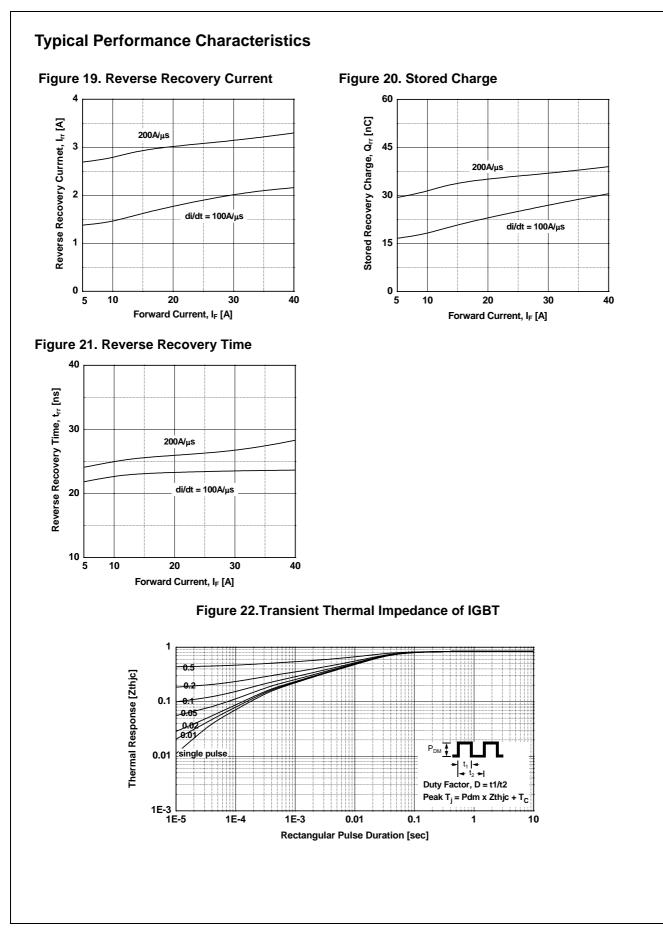
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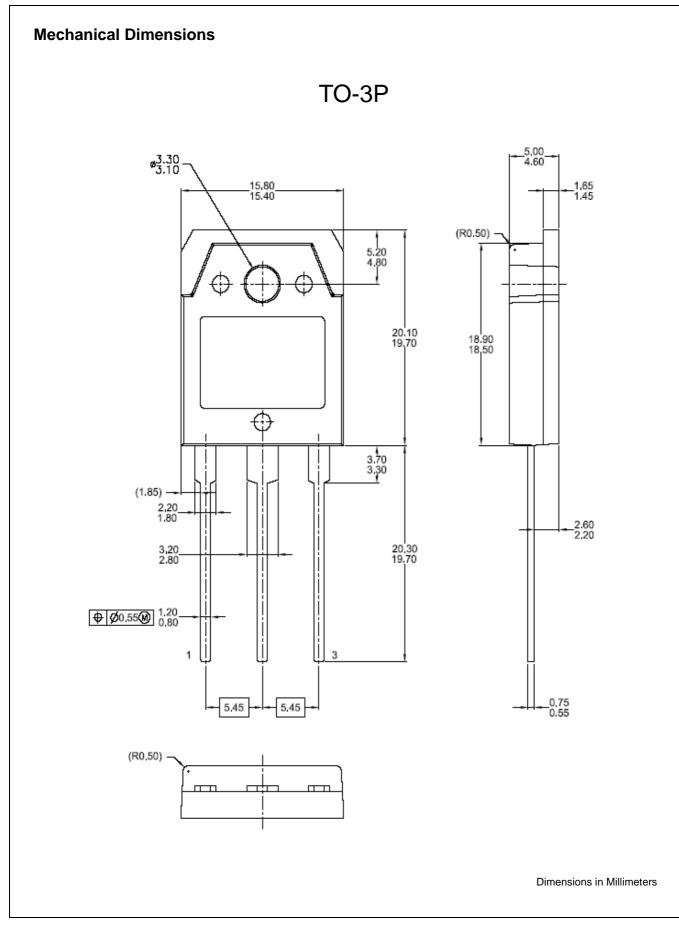
Gate Resistance, $R_G [\Omega]$

45

60









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